


<b>Search Notes</b>  	<b>Application/Control No.</b>  10518798	<b>Applicant(s)/Patent Under Reexamination</b>  OYAMA ET AL.
	<b>Examiner</b>  Le, Thao X	<b>Art Unit</b>  2814

SEARCHED			
Class	Subclass	Date	Examiner
257	98-100, E33.057, E33.059, E33.072	8/13/07	TL

SEARCH NOTES		
Search Notes	Date	Examiner
See print out	8/13/07	TL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner